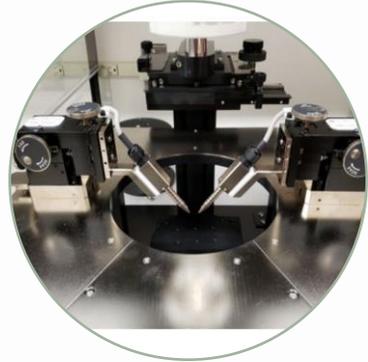


SUCCESSFUL APPLICATION: HIGH POWER - 0120



Specific Requirements:

A USA automotive manufacturer required a small footprint and flexible probing solution that would allow them to test 100 mm wafers, chips and packaged parts up to 200 amps. Volume was low so a manual probe system with manual manipulators and a variety of high current (HC) and low voltage DC probe arms were desired. The probe system would get interfaced to a Keysight B1506. Due to the lethal voltage levels required to test the devices, a safety enclosure was required.

SemiProbe Solution:

- LA-100 Lab Assistant manual 100 mm probe system:
 - 100 mm wafer chuck with High Voltage and 3 KV triaxial force and sense connections
- Microscope post with coaxial X and Y microscope movement of 100 mm x 100 mm with locking knobs
- Compound optics with CCTV system
- Two MA-9100 manual manipulators with high current probe arms and one MA-8005 with a coaxial DC probe arm
- Dark Box with door safety interlocks
- Interconnect panel:
 - Standard coaxial, triaxial, and 3 kV High Voltage triaxial connectors (force and sense)
 - Rubberized boot for direct passthrough for cables and safety interlock